

BWLF-5 MMIC Low pass Filter

Feature

- High Precision GaAs process
- •High performance, shielded
- GaAs substrate, 50 Ω CPW output
- Au wire bonding, for MCM applications

Environmental Specifications

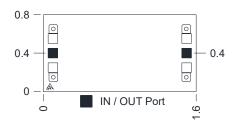
Operating Temperature	-55℃~+85℃	
Storage Temperature	-65°C~+150°C	
Max. Input Power	30dBm	

Electrical Specifications(T_A=+25°C)

Parameter	Min.	Тур.	Max.	Unit
Cut-off Freq. (fc)	-	5	-	GHz
Insertion Loss @ fc	-	-	1.7	dB
Return Loss	15	-	-	dB
Out of band	≥20@8.15GHz			dB
Attenuation	≥40@10.5GHz			dB

S2P file name: BWLF-5.s2p

Outline Drawing



Notes:

1. Dimensions are in millimeters. Tolerance: ±0.05mm

2. Die thickness is 0.1mm

3. Typical bond pad is 0.1x0.1 mm².

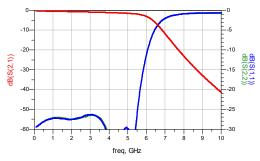
4. The bottom of the device is gold plated, should be grounded.

Typical Test Curves

Insertion Loss VS Frequency ($T_A=25^{\circ}C$)



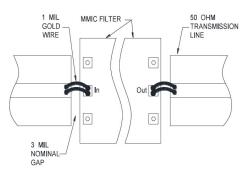




Broadband Insertion Loss VS Frequency (T_A=25°C)



Recommended Assembly Diagrams



Application Notes:

1. The chip is back-metallized and can be die-mounted with AuSn eutectic preforms or with electrically conductive epoxy.

2. The die should be assembled on carriers like Kovar or Mu-Cu which have same Coefficient of thermal expansion. (5.8×10-6/) with GaAs.

3. Recommend using $\Phi 25 \text{um}$ Au wire for bonding, whose length is around 400 \text{um}.

4. Sinter by AuSn (80/20), which doesn't exceed 300°C within 30 seconds max.

4. Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.

5. Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers.

6. The device is sensitive to ESD. ESD protection is required during storage and usage.

7. If you have any questions, please contact us.